

U.S. Patent Documents

				ont Documents			
Examiner						Sub-	Filing
Initial	No.	Patent No.	Date	Patentee	Class	class	Date
12	Α	6,314,460	11/06/2001	Knight et al.	709	220	10/30/1998
1	В	6,266,694	07/24/2001	Duguay et al.	709	223	06/19/1997
	С				D	ECEI	
	D				1.1		V C D
	E					FEB 1 5	2002
	F					LEDIO	2002
	G				Tech	ology Ce	nter 2100
	Н				-:	101097-00	INOI E 100
	I						
	J						
	K						

Foreign Patent or Published Foreign Patent Application

Examiner		Document	Publication	Country or		Sub-	Trans	lation
Initial	No.	No.	Date	Patent Office	Class	class	Yes	No
Ta)	L	01/84270	11/08/2001	WIPO	G06F			
	M	01/55862	08/02/2001	WIPO	G06F	13/00		
1 "	N	01/31539	05/03/2001	WIPO	G06F	17/60		
1,	0	00/77687	12/21/2000	WIPO	G06F	17/30		
V /	P	00/08806	02/17/2000	WIPO	H04L	12/26		
25	Q	98/42103	09/24/1998	WIPO	H04L	12/26		

Other Documents

		Other Documents
Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	R	
	S	
	T	1
Examiner		Frank Date Considered 4/12/2004
		7

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.